#### Accepted Manuscript

Numerical Ellipsometry: Use of parameter sensitivity to guide measurement selection for transparent anisotropic films

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PII: S0040-6090(18)30531-5

DOI: doi:10.1016/j.tsf.2018.07.047

Reference: TSF 36816

To appear in: Thin Solid Films

Received date: 27 March 2018
Revised date: 31 May 2018
Accepted date: 7 July 2018

Please cite this article as: F.K. Urban, D. Barton, Numerical Ellipsometry: Use of parameter sensitivity to guide measurement selection for transparent anisotropic films. Tsf (2018), doi:10.1016/j.tsf.2018.07.047

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# **ACCEPTED MANUSCRIPT**

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